

Estimating label quality and errors in semantic segmentation data via any model

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- **Problem/Objective**
 - Noisy label
- **Contribution/Key Idea**
 - Noisy label detection
 - 라벨 품질 평가하는 Softmin 알고리즘 제안
 - 라벨 품질이 낮다는 것은 부정확한 라벨이 많다는 것

- **Correctly Classified Pixels (CCP)**

모델 예측 결과와 라벨이 일치하는 비율

$$s_{CCP}(x) = \frac{\sum_{i,j} \mathbb{I}[l_{ij} = P_{ij}]}{h \cdot w} \quad (1)$$

- **Thresholded CCP (TCCP)**

CCP 에 클래스 별 임계값 도입

$$s_{TCCP,t}^k(x) = \frac{\sum_{i,j} \mathbb{I}[l_{ij} = k, p_{ijk} > \tau]}{h \cdot w} \quad (2)$$

$$\tau_k^* = \operatorname{argmax}_{\tau \in T} s_{TCCP,\tau}^k(x) \quad (3)$$

$$s_{TCCP}(x) = \frac{1}{K} \sum_{k=1}^K s_{TCCP,\tau_k^*}^k(x) \quad (4)$$

- Confidence In Label (CIL)

픽셀마다 라벨 품질 점수 구하고 이미지 단위 평균

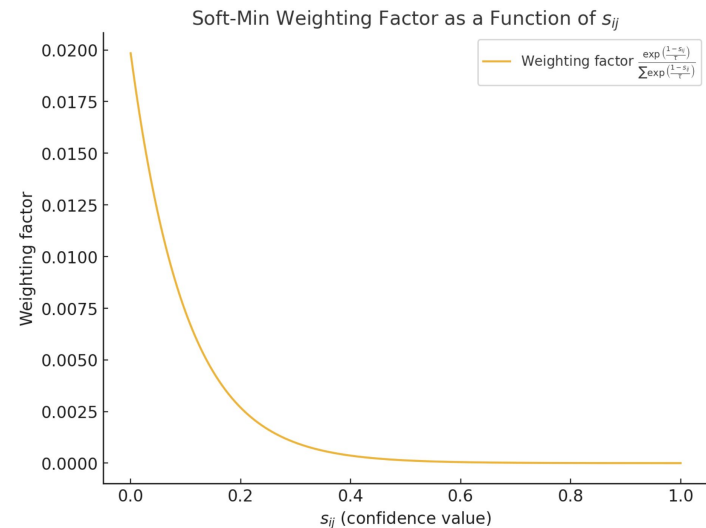
$$s_{CIL}(x) = \frac{1}{h \cdot w} \sum_{i,j} s_{ij} \quad (5)$$

$$s_{ij} := p_{i,j,l_{ij}}$$

- Softmin (Our Proposed Method)

라벨 품질 최소 점수를 soft approximation

$$s_{SM}(x) = \sum_{i,j} s_{ij} \cdot \frac{\exp\left(\frac{1-s_{ij}}{\tau}\right)}{\sum_{i,j} \exp\left(\frac{1-s_{ij}}{\tau}\right)} \quad (6)$$



- Confident Learning Counts (CLC)

이미지 내 라벨링 잘된 픽셀 비율

$$s_{CLC} = \frac{\sum_{i,j} b_{ij}}{h \cdot w} \quad (7)$$

- IOU

예측 마스크와 레이블 마스크 간 IoU

$$s_{IOU}(x) = \frac{|\mathbf{P} \cap \mathbf{I}|}{|\mathbf{P} \cup \mathbf{I}|} \quad (8)$$

- Connected Components (CoCo)

각 이미지 내 모든 연결 성분들의 평균 라벨 품질 점수

$$s_{CoCo}(x)$$

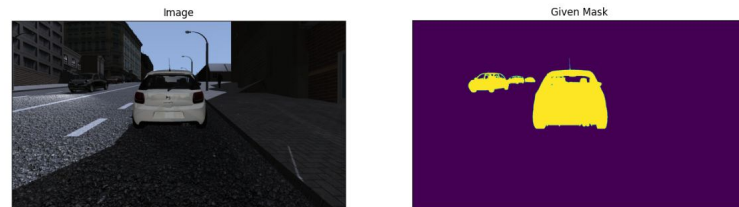
- Experiments

라벨 오류 유형 3가지

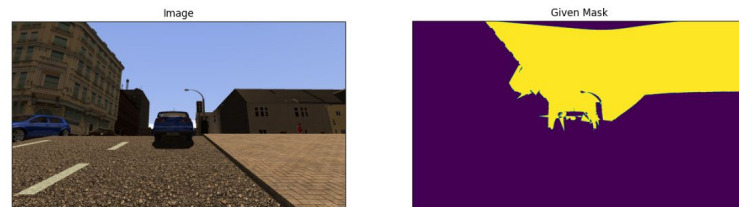
학습 및 검증 이미지 개수 : 1112개, 1112개

검증 세트에 대해서만 예측 및 라벨 품질 점수
계산함.

Drop (Car overlooked) - Given Mask for Unlabeled class



Shift Error (in Sky class) - Given Mask for Sky class



Swap (Building → Vegetation) - Given Mask for Vegetation



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- Experiments

Table 1. AUROC achieved by various label quality scores used with two types of models for detecting three types of annotation errors.

METHOD	DROP		SWAP		SHIFT	
MODEL	DEEPLABV3+	FPN	DEEPLABV3+	FPN	DEEPLABV3+	FPN
CORRECTLY CLASSIFIED PIXELS	0.915	0.916	1.000	1.000	0.833	0.798
THRESHOLDED CCP	0.869	0.869	0.993	0.993	0.852	0.818
CONFIDENCE IN LABEL	0.915	0.916	1.000	1.000	0.832	0.797
CONFIDENT LEARNING COUNTS	0.904	0.905	0.999	0.999	0.807	0.778
IoU	0.921	0.901	0.880	0.880	0.713	0.649
CONNECTED COMPONENTS	0.880	0.888	0.984	0.982	0.783	0.819
SOFTMIN	0.951	0.947	0.998	0.998	0.863	0.828

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Table 2. AUPRC achieved by various label quality scores used with two types of models for detecting three types of annotation errors.

ERROR TYPE	DROP		SWAP		SHIFT	
MODEL	DEEPLABV3+	FPN	DEEPLABV3+	FPN	DEEPLABV3+	FPN
CORRECTLY CLASSIFIED PIXELS	0.814	0.814	0.999	0.999	0.474	0.399
THRESHOLDED CCP	0.684	0.681	0.983	0.983	0.526	0.440
CONFIDENCE IN LABEL	0.813	0.814	0.999	0.999	0.472	0.398
CONFIDENT LEARNING COUNTS	0.795	0.796	0.999	0.999	0.429	0.375
IoU	0.808	0.749	0.754	0.759	0.440	0.320
CONNECTED COMPONENTS	0.654	0.675	0.971	0.965	0.519	0.537
SOFTMIN	0.888	0.875	0.996	0.996	0.545	0.461